# 2.5 V / 3.3 V / 5.0 V 1:4 Clock Fanout Buffer

## **NB3L553**

#### Description

The NB3L553 is a low skew 1-to 4 clock fanout buffer, designed for clock distribution in mind. The NB3L553 specifically guarantees low output-to-output skew. Optimal design, layout and processing minimize skew within a device and from device to device.

#### **Features**

- Input/Output Clock Frequency up to 200 MHz
- Low Skew Outputs (35 ps), Typical
- RMS Phase Jitter (12 kHz 20 MHz): 29 fs (Typical)
- Output goes to Three-State Mode via OE
- Operating Range:  $V_{DD} = 2.375 \text{ V}$  to 5.25 V
- 5 V Tolerant Input Clock ICLK
- Ideal for Networking Clocks
- Packaged in 8-pin SOIC
- Industrial Temperature Range
- These are Pb-Free Devices

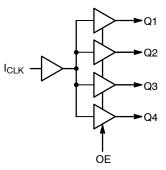


Figure 1. Block Diagram



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#### **MARKING DIAGRAMS\***



SOIC-8 D SUFFIX CASE 751



3L553 = Specific Device Code A = Assembly Location

L = Wafer Lot Y = Year W = Work Week ■ Pb-Free Package



#### DFN8 MN SUFFIX CASE 506AA



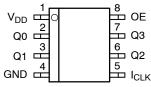
6P = Specific Device Code

 $\overline{M}$  = Date Code

= Pb-Free Package

(Note: Microdot may be in either location)

#### **PINOUT DIAGRAM**



#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NB3L553DG	SOIC-8 (Pb-Free)	98 Units/Rail
NB3L553DR2G	SOIC-8 (Pb-Free)	2500/Tape & Reel
NB3L553MNR4G	DFN-8 (Pb-Free)	1000/Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

<sup>\*</sup>For additional marking information, refer to Application Note AND8002/D.

Table 1. OE, OUTPUT ENABLE FUNCTION

OE	Function
0	Disable
1	Enable

### **Table 2. PIN DESCRIPTION**

Pin#	Name	Туре	Description
1	$V_{DD}$	Power	Positive supply voltage (2.375 V to 5.25 V)
2	Q0	(LV)CMOS/(LV)TTL Output	Clock Output 0
3	Q1	(LV)CMOS/(LV)TTL Output	Clock Output 1
4	GND	Power	Negative supply voltage; Connect to ground, 0 V
5	I <sub>CLK</sub>	(LV)CMOS Input	Clock Input. 5.0 V tolerant
6	Q2	(LV)CMOS/(LV)TTL Output	Clock Output 2
7	Q3	(LV)CMOS/(LV)TTL Output	Clock Output 3
8	OE	(LV)TTL Input	$V_{DD}$ for normal operation. Pin has no internal pullup or pull down resistor for open condition default. Use from 1 to 10 kOhms external resistor to force an open condition default state.
-	EP	Thermal Exposed Pad	(DFN8 only) Thermal exposed pad must be connected to a sufficient thermal conduit. Electrically connect to the most negative supply (GND) or leave unconnected, floating open.

**Table 3. MAXIMUM RATINGS** 

Symbol	Parameter	Condition 1	Condition 2	Rating	Unit
V <sub>DD</sub>	Positive Power Supply	GND = 0 V	-	6.0	V
V <sub>I</sub>	Input Voltage	OE I <sub>CLK</sub>	GND = 0 V and V <sub>DD</sub> = 2.375 V to 5.25 V	$\begin{aligned} & \text{GND} - 0.5 \leq V_{\text{I}} \leq V_{\text{DD}} + 0.5 \\ & \text{GND} - 0.5 \leq V_{\text{I}} \leq 5.75 \end{aligned}$	V
T <sub>A</sub>	Operating Temperature Range, Industrial	-	-	≥ -40 to ≤ +85	°C
T <sub>stg</sub>	Storage Temperature Range	-	-	-65 to +150	°C
θЈА	Thermal Resistance (Junction-to-Ambient)	0 Ifpm 500 Ifpm	SOIC-8	190 130	°C/W
θJC	Thermal Resistance (Junction-to-Case)	(Note 1)	SOIC-8	41 to 44	°C/W
$\theta_{\sf JA}$	Thermal Resistance (Junction-to-Ambient)	0 Ifpm 500 Ifpm	DFN8 DFN8	129 84	°C/W
θЈС	Thermal Resistance (Junction-to-Case)	(Note 1)	DFN8	35 to 40	°C/W

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. JEDEC standard multilayer board – 2S2P (2 signal, 2 power)

**Table 4. ATTRIBUTES** 

Chara	Value			
ESD Protection	> 2 kV > 150 V > 2 kV			
Moisture Sensitivity, Indefinite	Level 1			
Flammability Rating	Flammability Rating Oxygen Index: 28 to 34			
Transistor Count	531 Devices			
Meets or Exceeds JEDEC Standard EIA/JESD78 IC Latchup Test				

<sup>2.</sup> For additional Moisture Sensitivity information, refer to Application Note AND8003/D.

Table 5. DC CHARACTERISTICS ( $V_{DD}$  = 2.375 V to 2.625 V, GND = 0 V,  $T_A$  = -40°C to +85°C) (Note 3)

Symbol	Characteristic	Min	Тур	Max	Unit
I <sub>DD</sub>	Power Supply Current @ 135 MHz, No Load	-	25	30	mA
V <sub>OH</sub>	Output HIGH Voltage – I <sub>OH</sub> = –16 mA	1.7	-	-	V
V <sub>OL</sub>	Output LOW Voltage – I <sub>OL</sub> = 16 mA	-	-	0.4	V
V <sub>IH,</sub> I <sub>CLK</sub>	Input HIGH Voltage, I <sub>CLK</sub>		-	5.0	V
V <sub>IL,</sub> I <sub>CLK</sub>	Input LOW Voltage, I <sub>CLK</sub>	-	-	(V <sub>DD</sub> ÷2)-0.5	V
V <sub>IH,</sub> OE	Input HIGH Voltage, OE	1.8	-	$V_{DD}$	V
V <sub>IL,</sub> OE	Input LOW Voltage, OE	-	-	0.7	V
ZO	Nominal Output Impedance	-	20	-	Ω
CIN	Input Capacitance, I <sub>CLK</sub> , OE	-	5.0	-	pF
IOS	Short Circuit Current	-	± 28	-	mA

## DC CHARACTERISTICS (V<sub>DD</sub> = 3.15 V to 3.45 V, GND = 0 V, $T_A$ = $-40^{\circ}$ C to $+85^{\circ}$ C) (Note 3)

Symbol	Characteristic	Min	Тур	Max	Unit
I <sub>DD</sub>	Power Supply Current @ 135 MHz, No Load	-	35	40	mA
V <sub>OH</sub>	Output HIGH Voltage – I <sub>OH</sub> = -25 mA	2.4	-	-	٧
V <sub>OL</sub>	Output LOW Voltage – I <sub>OL</sub> = 25 mA	-	-	0.4	٧
V <sub>OH</sub>	Output HIGH Voltage – I <sub>OH</sub> = –12 mA (CMOS level)	V <sub>DD</sub> – 0.4	-	-	٧
V <sub>IH,</sub> I <sub>CLK</sub>	Input HIGH Voltage, I <sub>CLK</sub>	(V <sub>DD</sub> ÷2)+0.7	-	5.0	٧
V <sub>IL,</sub> I <sub>CLK</sub>	Input LOW Voltage, I <sub>CLK</sub>	-	-	(V <sub>DD</sub> ÷2)-0.7	٧
V <sub>IH,</sub> OE	Input HIGH Voltage, OE	2.0	-	$V_{DD}$	٧
V <sub>IL,</sub> OE	Input LOW Voltage, OE	0	_	0.8	V
ZO	Nominal Output Impedance	_	20	-	Ω
CIN	Input Capacitance, OE	_	5.0	_	pF
IOS	Short Circuit Current	_	± 50	_	mA

## DC CHARACTERISTICS (V<sub>DD</sub> = 4.75 V to 5.25 V, GND = 0 V, $T_A$ = $-40^{\circ}C$ to $+85^{\circ}C$ ) (Note 3)

Symbol	Characteristic	Min	Тур	Max	Unit
I <sub>DD</sub>	Power Supply Current @ 135 MHz, - No Load	-	45	85	mA
V <sub>OH</sub>	Output HIGH Voltage – I <sub>OH</sub> = -35 mA	2.4	-	-	V
V <sub>OL</sub>	Output LOW Voltage – I <sub>OL</sub> = 35 mA	-	-	0.4	V
V <sub>OH</sub>	Output HIGH Voltage – I <sub>OH</sub> = –12 mA (CMOS level)	V <sub>DD</sub> – 0.4	-	-	V
V <sub>IH,</sub> I <sub>CLK</sub>	Input HIGH Voltage, I <sub>CLK</sub>	(V <sub>DD</sub> ÷2) + 1	-	5.0	V
V <sub>IL,</sub> I <sub>CLK</sub>	Input LOW Voltage, I <sub>CLK</sub>	-	-	(V <sub>DD</sub> ÷2) – 1	V
V <sub>IH,</sub> OE	Input HIGH Voltage, OE	2.0	-	$V_{DD}$	V
V <sub>IL,</sub> OE	Input LOW Voltage, OE	-	-	0.8	V
ZO	Nominal Output Impedance	-	20	-	Ω
CIN	Input Capacitance, OE	-	5.0	-	pF
IOS	Short Circuit Current	-	± 80	-	mA

Table 6. AC CHARACTERISTICS;  $V_{DD}$  = 2.5 V ±5% ( $V_{DD}$  = 2.375 V to 2.625 V, GND = 0 V,  $T_A$  = -40°C to +85°C) (Note 3)

Symbol	Characteristic		Тур	Max	Unit
f <sub>in</sub>	Input Frequency		-	200	MHz
t <sub>r</sub> /t <sub>f</sub>	t <sub>f</sub> Output rise and fall times; 0.8 V to 2.0 V		1.0	1.5	ns
t <sub>pd</sub>	Propagation Delay, CLK to Q <sub>n</sub> (Note 4)		3.0	5.0	ns
t <sub>skew</sub>	t <sub>skew</sub> Output-to-output skew; (Note 5)		35	50	ps
t <sub>skew</sub>	Device-to-device skew, (Note 5)	-	-	500	ps

## AC CHARACTERISTICS; $V_{DD}$ = 3.3 V ±5% ( $V_{DD}$ = 3.15 V to 3.45 V, GND = 0 V, $T_{A}$ = -40°C to +85°C) (Note 3)

Symbol	Characteristic	Conditions	Min	Тур	Max	Unit
f <sub>in</sub>	Input Frequency		-	-	200	MHz
t <sub>jitter</sub> (φ)	RMS Phase Jitter (Integrated 12 kHz – 20 MHz) (See Figures 2 and 3)		-	18	-	fs
t <sub>r</sub> /t <sub>f</sub>	Output rise and fall times; 0.8 V to 2.0 V		-	0.6	1.0	ns
t <sub>pd</sub>	Propagation Delay, CLK to Q <sub>n</sub> (Note 4)		2.0	2.4	4.0	ns
t <sub>skew</sub>	Output-to-output skew; (Note 5)		-	35	50	ps
t <sub>skew</sub>	Device-to-device skew, (Note 5)		ı	ı	500	ps

## $\textbf{AC CHARACTERISTICS; V}_{DD} = \textbf{5.0 V} \pm \textbf{5\%} \ (V_{DD} = 4.75 \ V \ to \ 5.25 \ V, \ GND = 0 \ V, \ T_{A} = -40 ^{\circ} C \ to \ +85 ^{\circ} C) \ (Note \ 3)$

Symbol	Characteristic	Min	Min	Тур	Max	Unit
f <sub>in</sub>	Input Frequency		-	-	200	MHz
t <sub>jitter</sub> (φ)	RMS Phase Jitter (Integrated 12 kHz – 20 MHz) (See Figures 2 and 3)	f <sub>carrier</sub> = 100 MHz	-	29	-	fs
t <sub>r</sub> /t <sub>f</sub>	Output rise and fall times; 0.8 V to 2.0 V		-	0.3	0.7	ns
t <sub>pd</sub>	Propagation Delay, CLK to Q <sub>n</sub> (Note 4)		1.7	2.5	4.0	ns
t <sub>skew</sub>	Output-to-output skew; (Note 5)		-	35	50	ps
t <sub>skew</sub>	Device-to-device skew, (Note 5)		-	-	500	ps

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 3. Outputs loaded with external  $R_L = 33~\Omega$  series resistor and  $C_L = 15~pF$  to GND. Duty cycle out = duty in. A 0.01  $\mu$ F decoupling capacitor should

be connected between V<sub>DD</sub> and GND.

4. Measured with rail-to-rail input clock

<sup>5.</sup> Measured on rising edges at  $V_{DD} \div 2$  between any two outputs with equal loading.

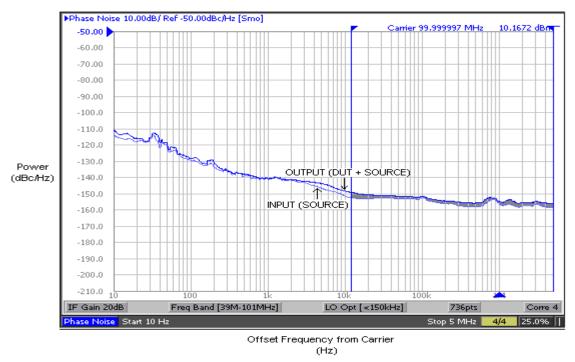


Figure 2. Phase Noise Plot at 100 MHz at an Operating Voltage of 3.3 V, Room Temperature

The above plot captured using Agilent E5052A shows Additive Phase Noise of the NB3L553 device measured with an input source generated by Agilent E8663B. The RMS phase jitter contributed by the device (integrated between 12 kHz to 20 MHz; as shown in the shaded area) is 18 fs (RMS Phase Jitter of the input source is 75.40 fs and Output (DUT+Source) is 93.16 fs).

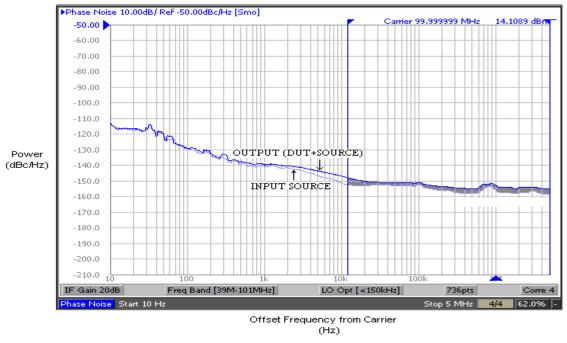


Figure 3. Phase Noise Plot at 100 MHz at an Operating Voltage of 5 V, Room Temperature

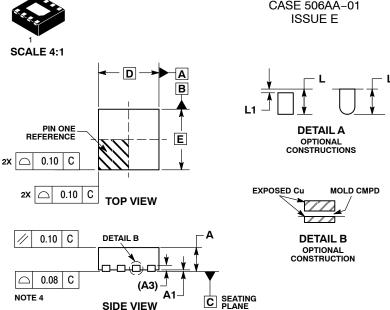
The above plot captured using Agilent E5052A shows Additive Phase Noise of the NB3L553 device measured with an input source generated by Agilent E8663B. The RMS phase jitter contributed by the device (integrated between 12 kHz to 20 MHz; as shown in the shaded area) is 29 fs (RMS Phase Jitter of the input source is 75.40 fs and Output (DUT+Source) is 103.85 fs).

DETAIL A

е

- D2 →

**BOTTOM VIEW** 



0.10 C

Ф

AB

0.05 C NOTE 3



**DATE 22 JAN 2010** 

#### NOTES

- DIMENSIONING AND TOLERANCING PER
- ASME Y14.5M, 1994 . CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION b APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN
- 0.15 AND 0.20 MM FROM TERMINAL TIP. COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.

	MULIMETERS				
	MILLIMETERS				
DIM	MIN	MAX			
Α	0.80	1.00			
A1	0.00	0.05			
A3	0.20	REF			
b	0.20	0.30			
D	2.00	BSC			
D2	1.10	1.30			
E	2.00	BSC			
E2	0.70	0.90			
е	0.50 BSC				
K	0.30 REF				
L	0.25	0.35			
L1		0.10			

#### **GENERIC MARKING DIAGRAM\***



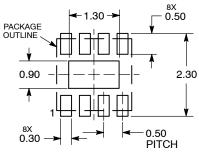
XX = Specific Device Code

= Date Code = Pb-Free Device

\*This information is generic. Please refer to device data sheet for actual part marking.

Pb-Free indicator, "G" or microdot " ■", may or may not be present.

#### **RECOMMENDED SOLDERING FOOTPRINT\***



**DIMENSIONS: MILLIMETERS** 

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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SOIC-8 NB CASE 751-07 **ISSUE AK** 

**DATE 16 FEB 2011** 



- NOTES:
  1. DIMENSIONING AND TOLERANCING PER
- ANSI Y14.5M, 1982.
  CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIMETERS		INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	4.80	5.00	0.189	0.197	
В	3.80	4.00	0.150	0.157	
С	1.35	1.75	0.053	0.069	
D	0.33	0.51	0.013	0.020	
G	1.27 BSC		0.050 BSC		
Н	0.10	0.25	0.004	0.010	
J	0.19	0.25	0.007	0.010	
K	0.40	1.27	0.016	0.050	
М	0 °	8 °	0 °	8 °	
N	0.25	0.50	0.010	0.020	
S	5.80	6.20	0.228	0.244	

#### **SOLDERING FOOTPRINT\***



<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### **GENERIC MARKING DIAGRAM\***



XXXXX = Specific Device Code = Assembly Location

= Wafer Lot = Year = Work Week

= Pb-Free Package



XXXXXX = Specific Device Code = Assembly Location Α

= Year ww = Work Week

= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

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#### SOIC-8 NB CASE 751-07 ISSUE AK

## DATE 16 FEB 2011

STYLE 4: PIN 1. ANODE 1 2. ANODE 2 3. ANODE 2 4. ANODE 5. ANODE #2 6. ANODE #2 7. ANODE #1 8. COMMON CATHODE
STYLE 8: PIN 1. COLLECTOR, DIE #1 2. BASE, #1 3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #2 STAGE Vd 7. EMITTER, #1 AGE Vd 8. COLLECTOR, #1
STYLE 12:  1 PIN 1. SOURCE 2 SOURCE 2 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
STYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2 4. BASE, DIE #2 5. COLLECTOR, DIE #2 6. COMMON 6. COLLECTOR, DIE #2 6. COMMON 7. COLLECTOR, DIE #1 6. COMMON 8. COLLECTOR, DIE #1
STYLE 20:  1 PIN 1. SOURCE (N) 2. GATE (N) 2 3. SOURCE (P) 4. GATE (P) 5. DRAIN 2 6. DRAIN 7. DRAIN 1 8. DRAIN
STYLE 24:   PIN 1. BASE     N ANODE/GND   2. EMITTER     N ANODE/GND   3. COLLECTOR/ANODE     UT   5. CATHODE     N ANODE/GND   6. CATHODE     N ANODE/GND   7. COLLECTOR/ANODE     UT   8. COLLECTOR/ANODE
STYLE 28: PIN 1. SW_TO_GND 2. DASIC_OFF 3. DASIC_SW_DET 4. GND E 5. V_MON E 6. VBULK E 7. VBULK 8. VIN

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NB7L1008MNG NB7L14MN1G PI49FCT20807QE PI6C4931502-04LIEX ZL80002QAB1 PI6C4931504-04LIEX PI6C10806BLEX
ZL40226LDG1 8T73S208B-01NLGI SY75578LMG PI49FCT32805QEX PL133-27GC-R CDCV304PWG4 MC10LVEP11DG
MC10EP11DTG MC100LVEP11DG MC100E111FNG MC100EP11DTG NB6N11SMNG NB7L14MMNG NB6L11MMNG
NB6L14MMNR2G NB6L611MNG PL123-02NGI-R NB3N111KMNR4G ADCLK944BCPZ-R7 ZL40217LDG1 NB7LQ572MNG
HMC940LC4BTR ADCLK946BCPZ-REEL7 ADCLK946BCPZ ADCLK854BCPZ ADCLK905BCPZ-R2 ADCLK905BCPZ-R7
ADCLK905BCPZ-WP